

Initial Product/Process Change Notification Document #: IPCN20912XA Issue Date: 23 October 2015

Title of Change:	Adding King Yuan Electronics Corp Taiwan (KYEC) as an additional Final Test Location	
Proposed first ship date:	23 February 2016 or Earlier upon customer approval	
Contact information:	Contact your local ON Semiconductor Sales Office or <tamara.olney@onsemi.com></tamara.olney@onsemi.com>	
Samples:	Samples should be available after completion of qualification. Contact your local ON Semiconductor Sales Office or <tamara.olney@onsemi.com></tamara.olney@onsemi.com>	
Type of notification:	This is an Initial Product/Process Change Notification (IPCN) sent to customers. IPCNs are issued at least 120 days prior to implementation of the change. An IPCN is advance notification about an upcoming change and contains general information regarding the change details and devices affected. It also contains the preliminary reliability qualification plan. The completed qualification and characterization data will be included in the Final Product/Process Change Notification (FPCN). This IPCN notification will be followed by a Final Product/Process Change Notification (FPCN) at least 90 days prior to implementation of the change. In case of questions, contact <pcn.support@onsemi.com>.</pcn.support@onsemi.com>	
Change category:	☐ Wafer Fab Change ☐ Assembly Change ☐ Test Chan	nge
Change Sub-Category(s): □ Datasheet/Product Doc change ☑ Manufacturing Site Change/Addition □ Material Change □ Shipping/Packaging/Marking □ Manufacturing Process Change □ Other:		
Sites Affected: All site(s) not applicable ON Semiconductor site(s): External Foundry/Subcon site(s) King Yuan Electronics Co., Ltd.		
Description and Purpose:		
	ics Corp Taiwan) as an additional test site to increase ON Semicon nction. KYEC is a qualified test house for ON Semiconductor.	ductor test capacity. This change does not
Qualification Plan:		
yield/bin correlation.	completion: 25 October 2015 iconductor 12MID07-0107. This includes repeatability tests, corre e performed and for every test the shift will be evaluated as follow	
dmean = abs(mean(ref)-mean(qual))	
dsigma = 0		if sigma(qual) < sigma(ref)
dsigma = sigma(qual) – sigma(r	ef)	if sigma(qual) > sigma(ref)
shift = dmean + 4 * dsigma		
If shift < max(5% specwidth, 6	*sigma(ref)) then correlation is OK for this test,	else correlation is NOK for this test
Any parameter that exceeds the	allowable shift is independently analysed and explained	

TEM001091 Rev. E Page 1 of 2



Initial Product/Process Change Notification Document #: IPCN20912XA Issue Date: 23 October 2015

Part Number	Qualification Vehicle
NCN5150DG	NCN5150DG
NCN5150DR2G	NCN5150DG
NCN5150MNTWG	NCN5150DG
SCY4001DR2G	SCY4001DR2G
NCS36000DG	NCS36000DG
NCS36000DRG	NCS36000DRG

TEM001091 Rev. E Page 2 of 2